



**Smart Cards;
UICC-Terminal interface;
Physical, electrical and logical test specification;
Part 1: Terminal features (Release 11)**

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Foreword

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The present document is part 2 of a multi-part deliverable covering the Test specification for the Terminal/Integrated Circuit Card (ICC) interface, as identified below:

Part 1: "Terminal features";

Part 2: "UICC features".

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In the present document "**shall**", "**shall not**", "**should**", "**should not**", "**may**", "**need not**", "**will**", "**will not**", "**can**" and "**cannot**" are to be interpreted as described in clause 3.2 of the [ETSI Drafting Rules](#) (Verbal forms for the expression of provisions).

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Introduction

The present document defines the interface tests for the Terminal/UICC interface.

The aim of the present document is to ensure interoperability between an UICC and a Terminal independently of the respective manufacturer, card issuer or operator.

Application specific tests for applications residing on an UICC are specified in ETSI TS 131 121 [4].

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